

**Search Notes**

Application/Control No.

09/274,015

Examiner

EDMUND H. LEE

Applicant(s)/Patent under  
Reexamination

HEBERT ET AL.

Art Unit

1732

**SEARCHED**

| Class   | Subclass | Date      | Examiner |
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| UPDATED |          | 6/13/2005 | EHL      |
|         |          | 2/6/2006  | EHL      |
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**INTERFERENCE SEARCHED**

| Class | Subclass | Date     | Examiner |
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| 264   | 255      | 2/6/2006 | EHL      |
|       | 275      |          |          |
|       | 279.1    |          |          |
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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|         | DATE     | EXMR |
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| UPDATED | 2/6/2006 | EHL  |
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